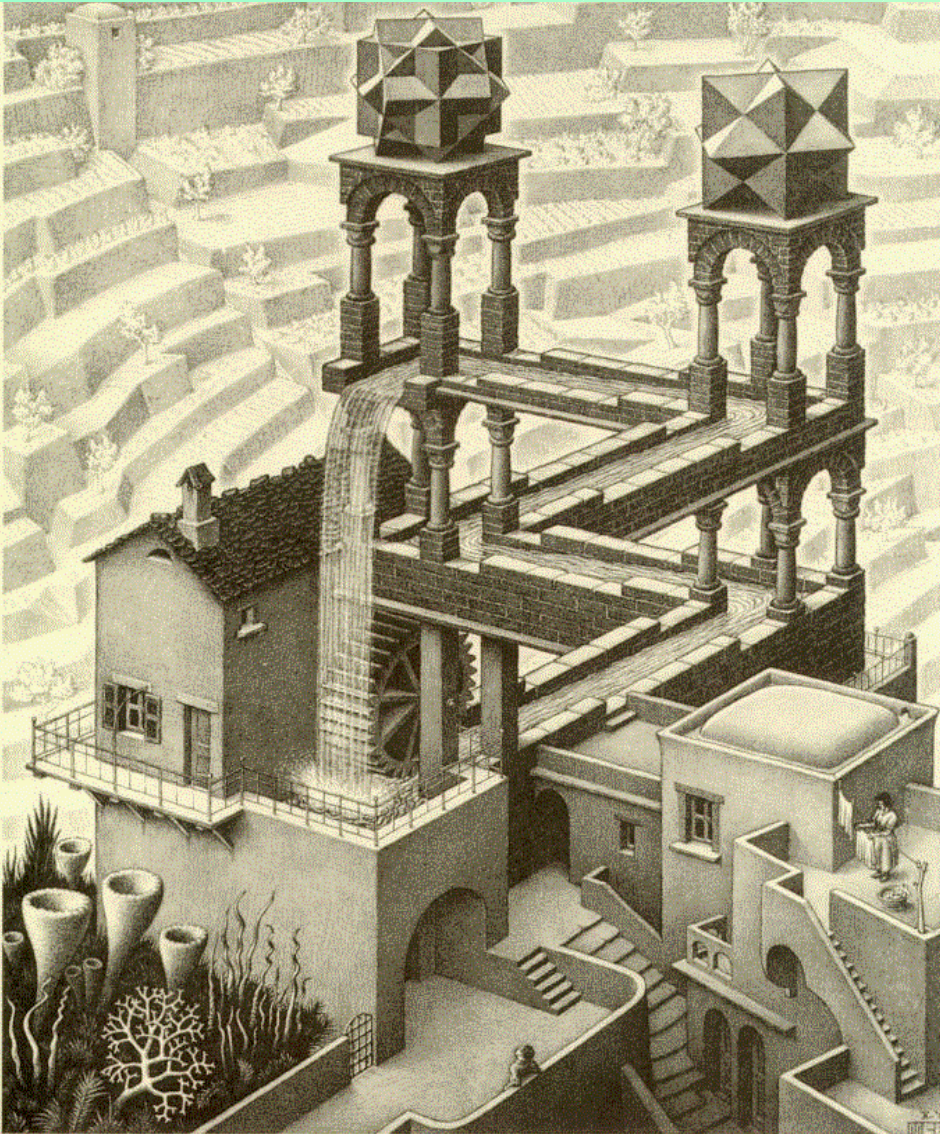


# Interferences: Pathological and Otherwise



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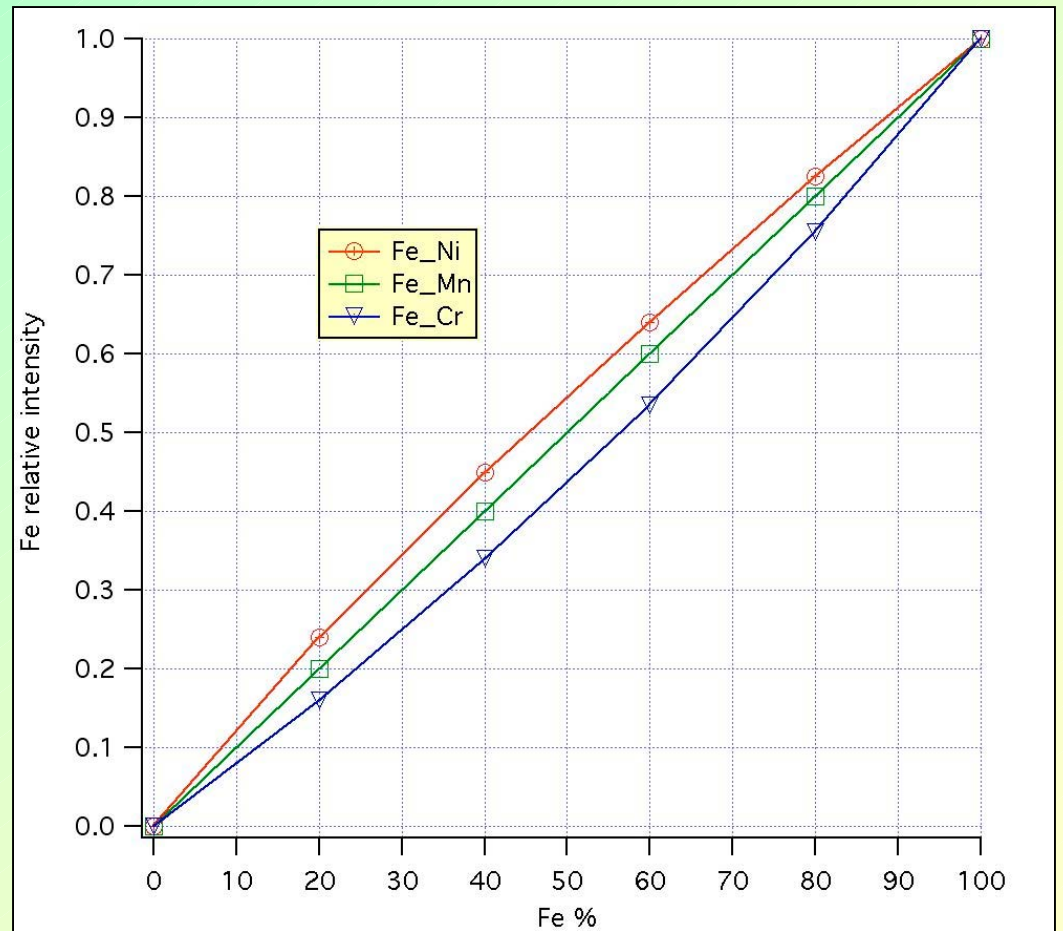
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# Matrix Correction

$$C_i^{unk} \approx \frac{I_i^{unk}}{I_i^{std}} C_i^{std}$$

$$C_i^{unk} = \frac{I_i^{unk}}{I_i^{std}} \frac{ZAF_i^{unk}}{ZAF_i^{std}} C_i^{std}$$



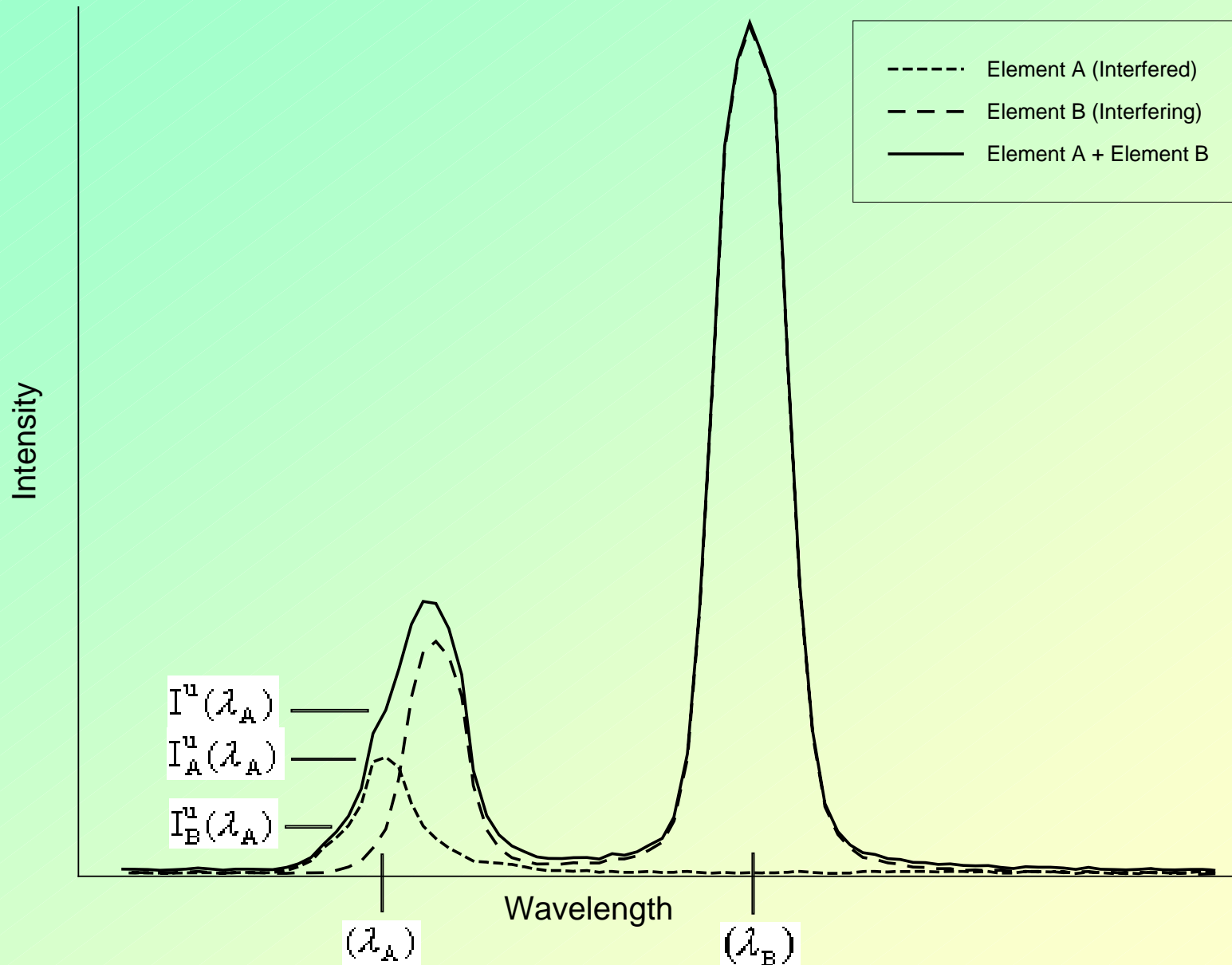
from Fournelle



# Other Compositionally Dependent Corrections

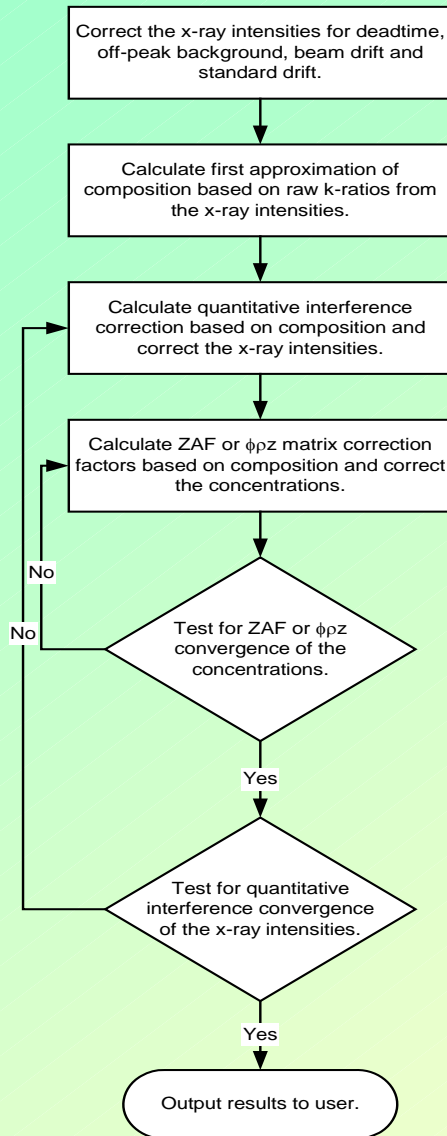
- Quantitative Spectral Interference Calculations
- Mean Atomic Number (MAN) Based Backgrounds
- Volatile Intensity Corrections
- Water by Difference (specified element effects)
- Compound Area-Peak Factor (APF) Calculations
- Blank (Zero) Value Corrections for Trace Elements

# Spectral Interferences



# Matrix Iteration

Flow Diagram of the Quantitative Iterated Interference Correction



Eq. 1

$$I_B^u(\lambda_A) \approx \frac{I_B^{\bar{s}}(\lambda_A) I_B^u(\lambda_B)}{C_B^{\bar{s}} I_B^s(\lambda_B)} C_B^s$$

Gilfrich, *et al.*, 1978

Eq. 2

$$I_B^U(\lambda_A) = \frac{[ZAF]_{\lambda_A}^{\bar{s}} C_B^u}{C_B^{\bar{s}} [ZAF]_{\lambda_A}^u} I_B^{\bar{s}}(\lambda_A)$$

Donovan, Rivers and Snyder, 1993

$$C_A^u = \frac{C_A^s}{[ZAF]_{\lambda_A}^s} \frac{I^u(\lambda_A) - \frac{[ZAF]_{\lambda_A}^{\bar{s}} C_B^u}{C_B^{\bar{s}} [ZAF]_{\lambda_A}^u} I_B^{\bar{s}}(\lambda_A)}{I_A^s(\lambda_A)}$$

# Differences Between Eq. 1 and Eq. 2

## *Self-Interfering Analyses*

	wt. % (nominal)	wt. % (uncorrected)	wt. % (Eq. 1)	wt. % (Eq. 2)
Ba L $\alpha$ $\leftrightarrow$ Ti K $\alpha$ (PET)	Ba 33.15 <sup>3</sup>	33.26 $\pm$ 0.18	33.08	33.08 $\pm$ 0.18
	Ti 11.69	11.71 $\pm$ 0.08	11.59	11.59 $\pm$ 0.08
Pb L $\alpha$ $\leftrightarrow$ As K $\alpha$	Pb 59.69 <sup>4</sup>	106.20 $\pm$ 0.33	19.64	61.25 $\pm$ 1.97
	As 21.58	41.38 $\pm$ 0.27	6.60	22.15 $\pm$ 1.04

<sup>3</sup> Benitoite (BaTiSi<sub>3</sub>O<sub>9</sub>) is assumed stoichiometric : Si 20.38, Ba 33.15, Ti 11.69, O 34.896

<sup>4</sup> Shultenite (HAsPbO<sub>4</sub>) is assumed stoichiometric : Pb 59.69, As 21.58, O 18.44. The oxygen concentration was measured at 19.8 wt. % and included in the matrix correction calculations.

	Pb L $\alpha$ (cps)	As K $\alpha$ (cps)	S K $\alpha$ (cps)
PbS	1473.3 $\pm$ 11.5	1213.0 $\pm$ 3.8	1453.3 $\pm$ 9.3
GaAs	1624.7 $\pm$ 29.9	1771.7 $\pm$ 8.2	2.5 $\pm$ 1.2
FeS	14.0 $\pm$ 3.3	13.9 $\pm$ 3.7	4986.9 $\pm$ 26.3

## *Cascade Interference Analyses*

	wt. % (nominal)	wt. % (uncorrected)	wt. % (Eq. 1)	wt. % (Eq. 2)
Ni K $\rightarrow$ Fe K $\alpha$ Fe K $\beta$ $\rightarrow$ Co K $\alpha$	Co 0.022 <sup>1</sup>	0.089 $\pm$ 0.008	0.010	0.022 $\pm$ 0.008
Ti K $\beta$ $\rightarrow$ V K $\alpha$ V K $\beta$ $\rightarrow$ Cr K $\alpha$	Cr 0.025 <sup>2</sup>	0.268 $\pm$ 0.01	-0.020	0.021 $\pm$ 0.010

<sup>1</sup> SRM 1159 includes : Ni 48.2, Fe 51.0, C 0.007, Mn 0.30, P 0.003, S 0.003, Si 0.32, Cu 0.038, Cr 0.06, Mo 0.01

<sup>2</sup> SRM 654b includes : Ti 88.974, Al 6.34, V 4.31, Fe 0.23, Si 0.045, Ni 0.028, Sn 0.023, Cu 0.004, Mo 0.013, Zr 0.008

# Pathological Interferences

Un 10 Zn-ReSCN gr2  
 TakeOff = 40 KiloVolts = 20 Beam Current = 20 Beam Size = 0

## Results in Elemental Weight Percents

SPEC:	O	N	C	H
TYPE:	SPEC	SPEC	SPEC	SPEC
AVER:	1.900	5.000	4.200	.200
SDEV:	.000	.000	.000	.000

Re la 1.43298  
 Zn ka 1.43652

ELEM:	Cs	Fe	Zn	Re	S	Se	SUM
53	.000	.000	19.463	74.142	17.309	.000	122.214
55	.000	.007	20.459	74.986	16.357	.000	123.108
56	.000	.019	19.578	75.195	17.997	.000	124.089
AVER:	.000	.009	19.833	74.774	17.221	.000	123.137
SDEV:	.000	.010	.545	.558	.824	.000	
SERR:	.000	.006	.314	.322	.476	.000	
%RSD:	.1	113.3	2.7	.7	4.8	.1	
STDS:	834	730	660	575	730	660	



“Self-Interfering”

## Results Based on 6 Atoms of re

SPEC:	O	N	C	H
TYPE:	SPEC	SPEC	SPEC	SPEC
AVER:	1.774	5.334	5.225	2.965
SDEV:	.013	.040	.039	.022

ELEM:	Cs	Fe	Zn	Re	S	Se	SUM
53	.000	.000	4.486	6.000	8.134	.000	34.048
55	.000	.002	4.663	6.000	7.600	.000	33.518
56	.000	.005	4.450	6.000	8.339	.000	34.005
AVER:	.000	.002	4.533	6.000	8.025	.000	33.857
SDEV:	.000	.003	.114	.000	.382	.000	
SERR:	.000	.001	.066	.000	.220	.000	
%RSD:	.8	113.2	2.5	.0	4.8	.8	



# With Iterated Interference Correction

Un 10 Zn-ReSCN gr2  
 TakeOff = 40 KiloVolts = 20 Beam Current = 20 Beam Size = 0

## Results in Elemental Weight Percents

SPEC:	O	N	C	H			
TYPE:	SPEC	SPEC	SPEC	SPEC			
AVER:	1.900	5.000	4.200	.200			
SDEV:	.000	.000	.000	.000			
ELEM:	Cs	Fe	Zn	Re	S	Se	SUM
53	.000	.000	6.325	65.726	17.333	.000	100.683
55	.000	.007	7.471	65.113	16.343	.000	100.233
56	.000	.019	6.188	66.949	18.029	.000	102.486
AVER:	.000	.009	6.661	65.929	17.235	.000	101.134
SDEV:	.000	.010	.704	.935	.848	.000	
SERR:	.000	.006	.407	.540	.489	.000	
%RSD:	.1	113.3	10.6	1.4	4.9	.0	
STDS:	834	730	660	575	730	660	

## Results Based on 6 Atoms of re

SPEC:	O	N	C	H			
TYPE:	SPEC	SPEC	SPEC	SPEC			
AVER:	2.013	6.050	5.926	3.363			
SDEV:	.028	.085	.084	.047			
ELEM:	Cs	Fe	Zn	Re	S	Se	SUM
53	.000	.000	1.645	6.000	9.189	.000	34.236
55	.000	.002	1.961	6.000	8.745	.000	34.274
56	.000	.006	1.580	6.000	9.383	.000	34.053
AVER:	.000	.003	1.728	6.000	9.106	.000	34.188
SDEV:	.000	.003	.204	.000	.327	.000	
SERR:	.000	.002	.118	.000	.189	.000	
%RSD:	1.3	112.3	11.8	.0	3.6	1.4	

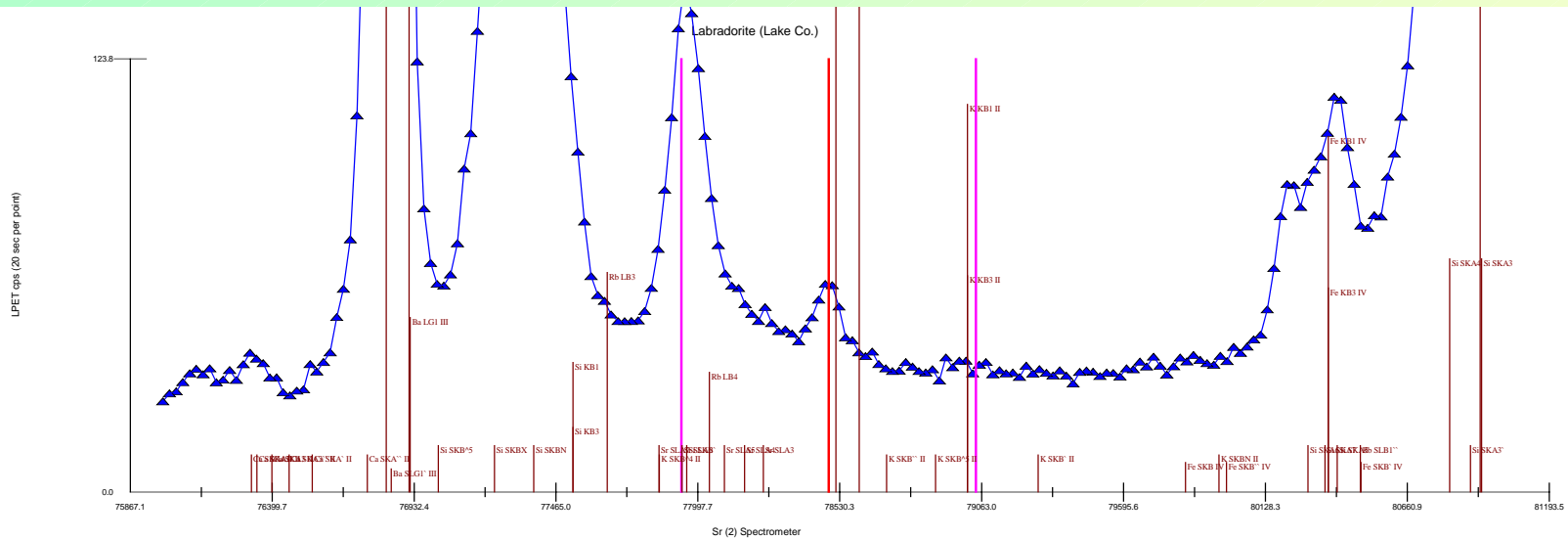
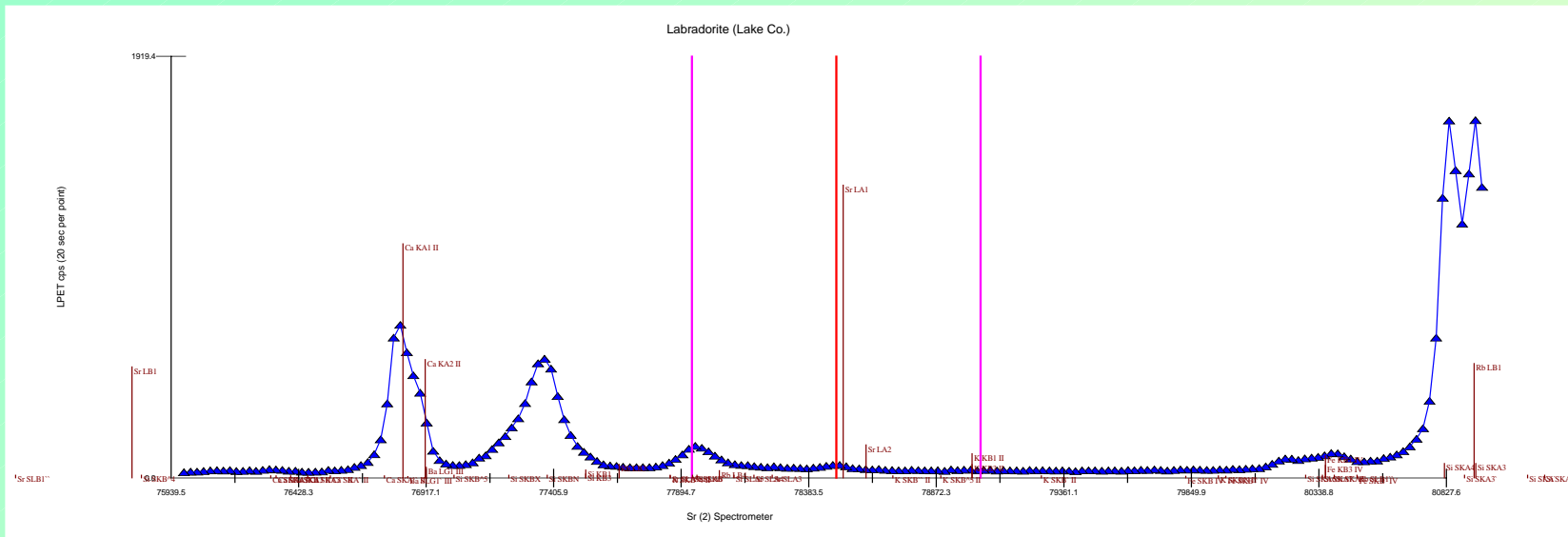
6 rhenium to 9 sulfur

# Large magnitude “Self-Interferences”

Interfering Pair	Wavelength Region (Å)	Approximate Overlap (% @ 50/50)
Ba L $\alpha$ $\leftrightarrow$ Ti K $\alpha$	2.7	0.8 - 0.2
Pb L $\alpha$ $\leftrightarrow$ As K $\alpha$	1.17	150 - 65
Hg L $\alpha$ $\leftrightarrow$ Ge K $\alpha$	1.25	120 - 15
Ir L $\alpha$ $\leftrightarrow$ Ga K $\alpha$	1.34	70 - 30
Re L $\alpha$ $\leftrightarrow$ Zn K $\alpha$	1.43	140 - 60
Er L $\alpha$ $\leftrightarrow$ Co K $\alpha$	1.78	110 - 50
Eu L $\alpha$ $\leftrightarrow$ Mn K $\alpha$	2.1	15 - 5
In L $\alpha$ $\leftrightarrow$ K K $\alpha$	3.74	50 - 20
Th M $\alpha$ $\leftrightarrow$ Ag L $\alpha$	4.13	30 - 60
Bi M $\alpha$ $\leftrightarrow$ Tc L $\alpha$	5.1	50 - 70
Mo L $\alpha$ $\leftrightarrow$ S K $\alpha$	5.4	30 - 15

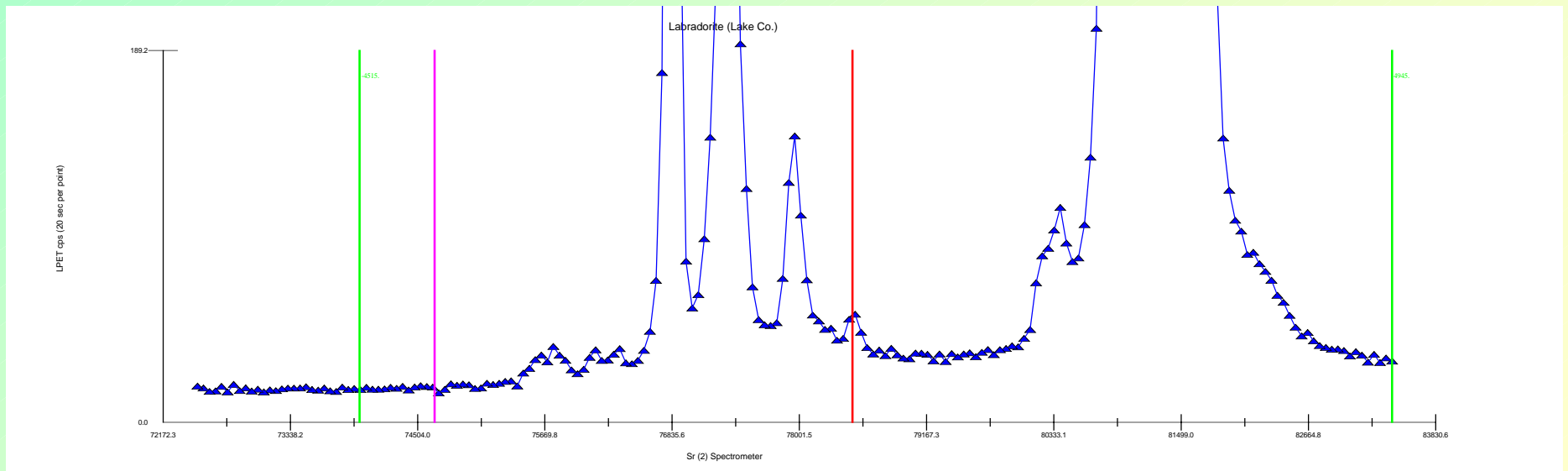
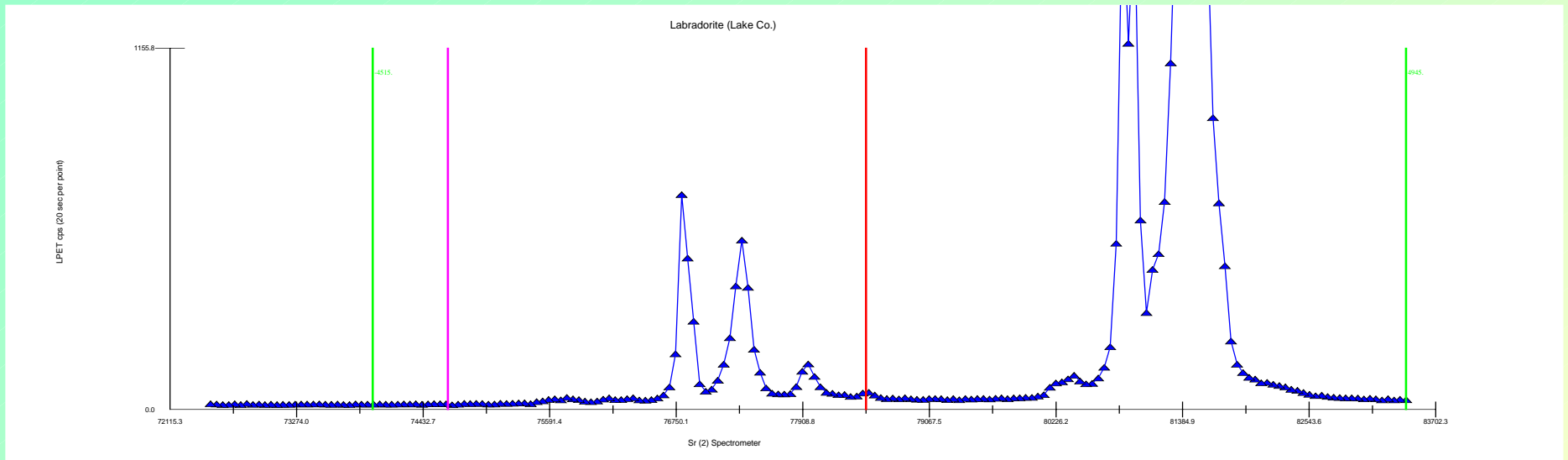
# Typical (nasty) Interference, but first...

20 keV  
100 nA  
PET





# How about now?



# Polygonization...

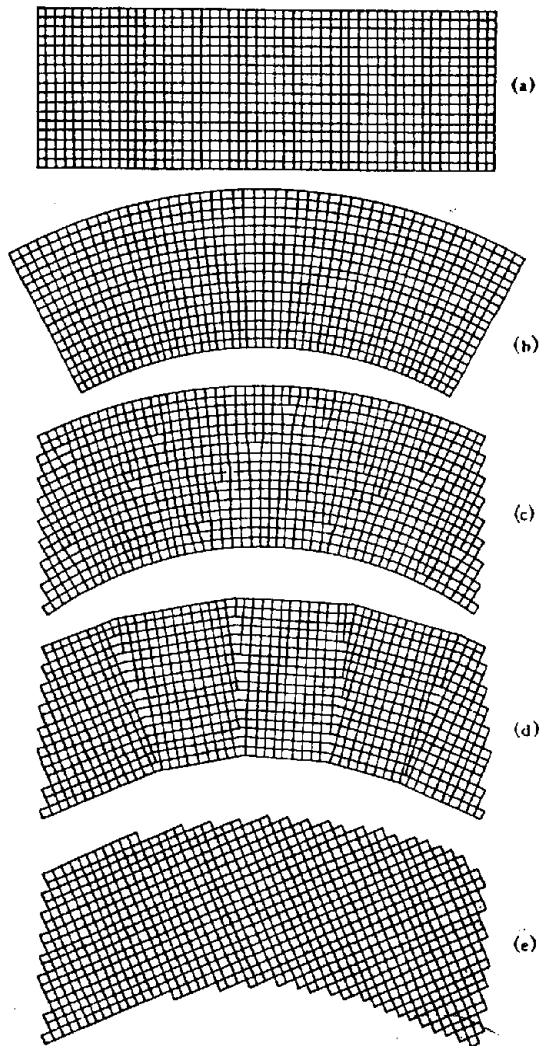
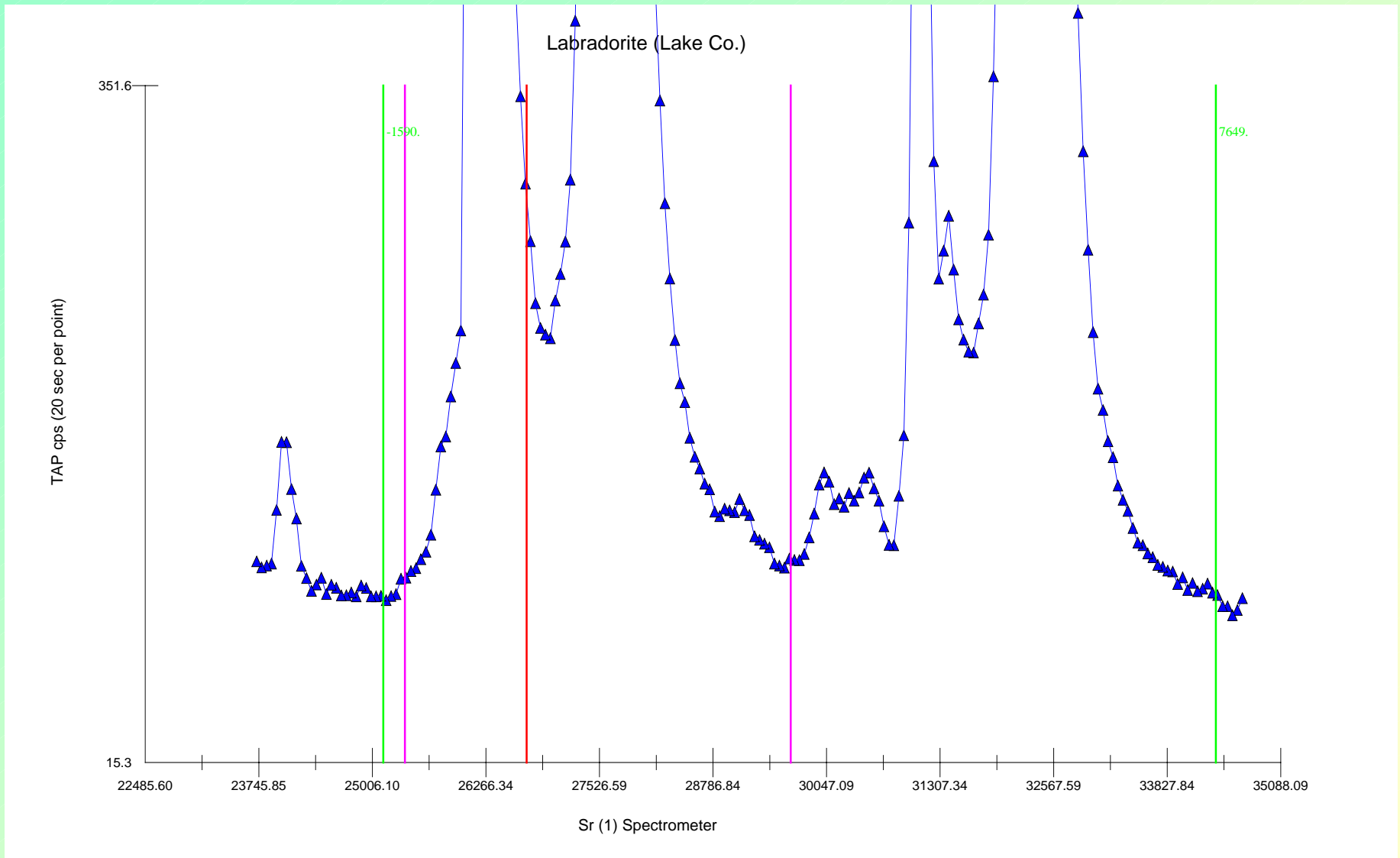


FIG. 1.27. Five states of a single crystal. (a) Unstrained. (b) Elastically bent. (c) Plastically bent. (d) Polygonized. (e) Recrystallized.

Nabarro, F.R.N. (1967) Theory of Crystal Dislocations, Oxford, 821 pp.

# Can we measure “true” background between Al and Si ka peaks?



# Results

SiO<sub>2</sub>, WITHOUT Interference Correction:

	Sr (Ia) TAP	Sr (Ia) LPET	Sr (Ia) LPET	Sr (Ia) TAP
Average:	0.505	0.071	0.070	0.399
Std Dev:	0.010	0.001	0.003	0.004

SiO<sub>2</sub>, WITH Interference Correction:

	Sr (Ia) TAP	Sr (Ia) LPET	Sr (Ia) LPET	Sr (Ia) TAP
Average:	0.003	0.002	0.000	-0.001
Std Dev:	0.012	0.001	0.004	0.003



# Conclusions

- Quantitative interference corrections require accurate background measurements
- Even “pathological” cascade and self-interfering interference correction are routine using iterative correction methods